

**Search Notes**

Application/Control No.

10/773,802

Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

WON ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
216	24	10/24/2006	BT
216	60	10/24/2006	BT
216	72	10/24/2006	BT
216	79	10/24/2006	BT

**INTERFERENCE SEARCHED**

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216	24	10/24/2006	BT
216	60	10/24/2006	BT
216	72	10/24/2006	BT
216/79		10/24/2006	BT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update keywords search using USPAT, USPG-PUB, JPO, EPO, DERWENT database	10/24/2006	BT